

TEXAS INSTR (OPTO)

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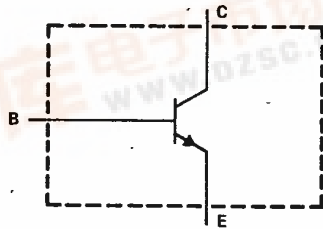
TIPL751, TIPL751A  
N-P-N SILICON POWER TRANSISTORS

T-33-13

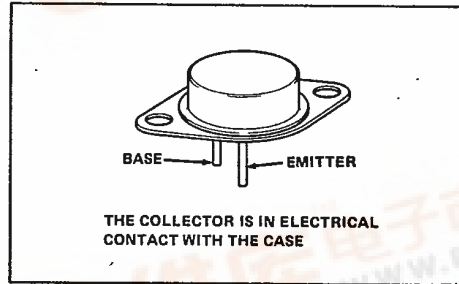
OCTOBER 1982 - REVISED OCTOBER 1984

- 120 W at 25°C Case Temperature
- 4 A Continuous Collector Current
- 8 A Peak Collector Current
- Operating Characteristics Fully Guaranteed at 100°C
- Transient Power Dissipation Guaranteed at 100°C
- ICES < 100 μA at Maximum Rated VCE at 100°C
- 1000 V Blocking Capability
- High Sustaining Voltage  
TIPL751 ... 375 V Min.  
TIPL751A ... 420 V Min.
- Designed for High-Voltage, Inductive-Load Switching Applications

device schematic



TO-3 PACKAGE



absolute maximum ratings at 25°C case temperature (unless otherwise noted)

	TIPL751	TIPL751A
Collector-base voltage ( $I_E = 0$ )	800 V	1000 V
Collector-emitter voltage ( $V_{BE} = 0$ )	800 V	1000 V
Collector-emitter voltage ( $I_B = 0$ )	375 V	420 V
Base-emitter voltage	10 V	
Continuous collector current	4 A	
Peak collector current (see Note 1)	8 A	
Continuous device dissipation at (or below) 25°C case temperature (see Figure 12)	120 W	
Operating junction and storage temperature range	-65°C to 200°C	

NOTE 1: This value applies for  $t_w \leq 10$  ms, duty cycle  $\leq 2\%$ .

TIPL Devices



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**TIPL751, TIPL751A  
N-P-N SILICON POWER TRANSISTORS**

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**electrical characteristics at 25°C case temperature (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	TIPL751			TIPL751A			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	
V <sub>CEO(sus)</sub>	I <sub>C</sub> = 100 mA, L = 25 mH, See Note 2	375			420			V
I <sub>CEO</sub>	V <sub>CE</sub> = 375 V, I <sub>B</sub> = 0		50					μA
	V <sub>CE</sub> = 420 V, I <sub>B</sub> = 0					50		
I <sub>CES</sub>	V <sub>CE</sub> = 800 V, V <sub>BE</sub> = 0		50					μA
	V <sub>CE</sub> = 800 V, V <sub>BE</sub> = 0, T <sub>C</sub> = 100°C		100					
	V <sub>CE</sub> = 1000 V, V <sub>BE</sub> = 0					50		
	V <sub>CE</sub> = 1000 V, V <sub>BE</sub> = 0, T <sub>C</sub> = 100°C					100		
I <sub>EBO</sub>	V <sub>EB</sub> = 10 V, I <sub>C</sub> = 0		1			1		mA
h <sub>FE</sub>	V <sub>CE</sub> = 5 V, I <sub>C</sub> = 0.5 A, See Notes 3 and 4	20	60		20	60		
V <sub>CE(sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 0.2 A, See Notes 3 and 4		0.5			0.5		V
	I <sub>C</sub> = 2.5 A, I <sub>B</sub> = 0.5 A, See Notes 3 and 4		1			1		
	I <sub>C</sub> = 4 A, I <sub>B</sub> = 0.8 A, See Notes 3 and 4		2.5			2.5		
	I <sub>C</sub> = 4 A, I <sub>B</sub> = 0.8 A, See Notes 3 and 4, T <sub>C</sub> = 100°C		5			5		
V <sub>BE(sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 0.2 A, See Notes 3 and 4		1			1		V
	I <sub>C</sub> = 2.5 A, I <sub>B</sub> = 0.5 A, See Notes 3 and 4		1.2			1.2		
	I <sub>C</sub> = 4 A, I <sub>B</sub> = 0.8 A, See Notes 3 and 4		1.4			1.4		
	I <sub>C</sub> = 4 A, I <sub>B</sub> = 0.8 A, See Notes 3 and 4, T <sub>C</sub> = 100°C		1.3			1.3		
f <sub>T</sub>	V <sub>CE</sub> = 10 V, I <sub>C</sub> = 0.5 A, See Note 5		12			12		MHz
C <sub>obo</sub>	V <sub>CB</sub> = 20 V, I <sub>E</sub> = 0, f = 0.1 MHz		110			110		pF

- NOTES: 2. Inductive loop switching measurement.  
 3. These parameters must be measured using pulse techniques, t<sub>W</sub> = 300 μs, duty cycle < 2%.  
 4. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts and located within 3.2 mm (0.125 inch) from the device body.  
 5. To obtain f<sub>T</sub>, the |h<sub>FE</sub>| response is extrapolated at the rate of -6 dB per octave from f = MHz to the frequency at which |h<sub>FE</sub>| = 1.

**thermal characteristics**

PARAMETER	MIN	TYP	MAX	UNIT
R <sub>θJC</sub>		1.46		°C/W

**resistive-load switching characteristics at 25°C case temperature (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>on</sub>	I <sub>C</sub> = 4 A, V <sub>CC</sub> = 200 V, I <sub>B1</sub> = 0.8 A, I <sub>B2</sub> = -0.8 A, T <sub>C</sub> = 25°C, See Figure 1		0.55		μs
t <sub>s</sub>			2.5		μs
t <sub>f</sub>			0.5		μs
t <sub>on</sub>	I <sub>C</sub> = 4 A, V <sub>CC</sub> = 200 V, I <sub>B1</sub> = 0.8 A, I <sub>B2</sub> = -0.8 A, T <sub>C</sub> = 100°C, See Figure 1		0.65		μs
t <sub>s</sub>			3		μs
t <sub>f</sub>			1		μs

**inductive-load switching characteristics at 25°C case temperature (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>sv</sub>	I <sub>C</sub> = 4 A, I <sub>B1</sub> = 0.8 A, T <sub>C</sub> = 25°C, V <sub>BE(off)</sub> = -5 V, See Figure 2		2.5		μs
t <sub>rv</sub>			0.3		μs
t <sub>fi</sub>			0.25		μs
t <sub>ti</sub>			0.15		μs
t <sub>xo</sub>			0.4		μs
t <sub>sv</sub>			3		μs
t <sub>rv</sub>	I <sub>C</sub> = 4 A, I <sub>B1</sub> = 0.8 A, T <sub>C</sub> = 100°C, V <sub>BE(off)</sub> = -5 V, See Figure 2		0.5		μs
t <sub>fi</sub>			0.25		μs
t <sub>ti</sub>			0.15		μs
t <sub>xo</sub>			0.75		μs

TIPL Devices



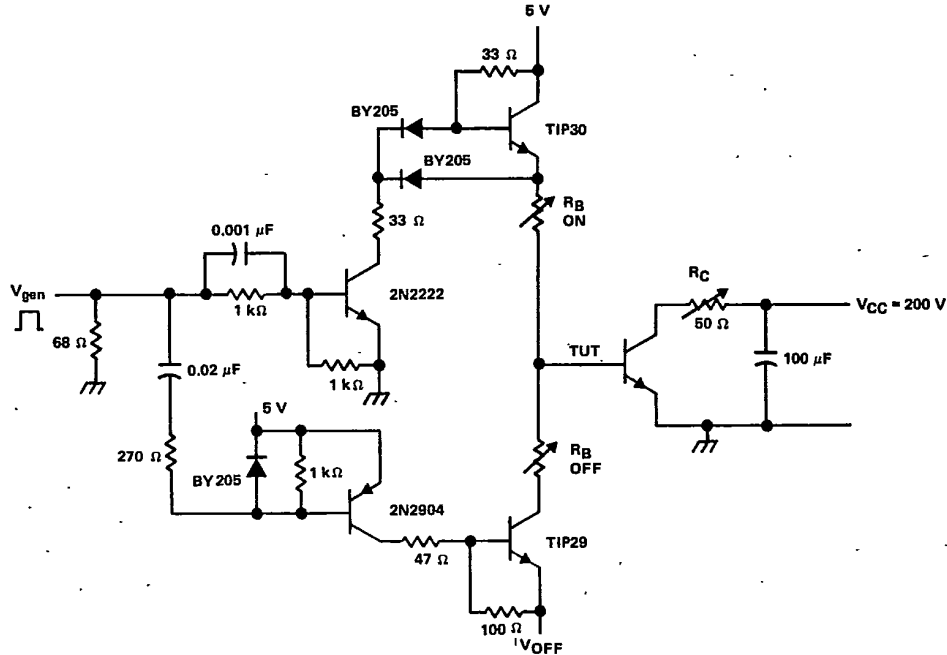
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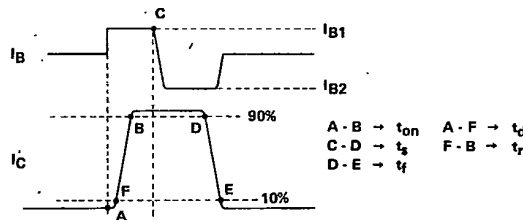
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PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



VOLTAGE WAVEFORMS

- NOTES: A. The  $V_{gen}$  waveform is supplied by a generator with the following characteristics:  $t_r \leq 15 \text{ ns}$ ,  $t_f \leq 15 \text{ ns}$ ,  $Z_{out} = 50 \Omega$ ,  $t_w = 20 \mu\text{s}$  duty cycle  $\leq 2\%$ .  
 B. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r \leq 15 \text{ ns}$ ,  $R_{in} \geq 10 \text{ M}\Omega$ ,  $C_{in} \leq 11.5 \text{ pF}$ .  
 C. Resistors must be noninductive types.

FIGURE 1. RESISTIVE-LOAD SWITCHING

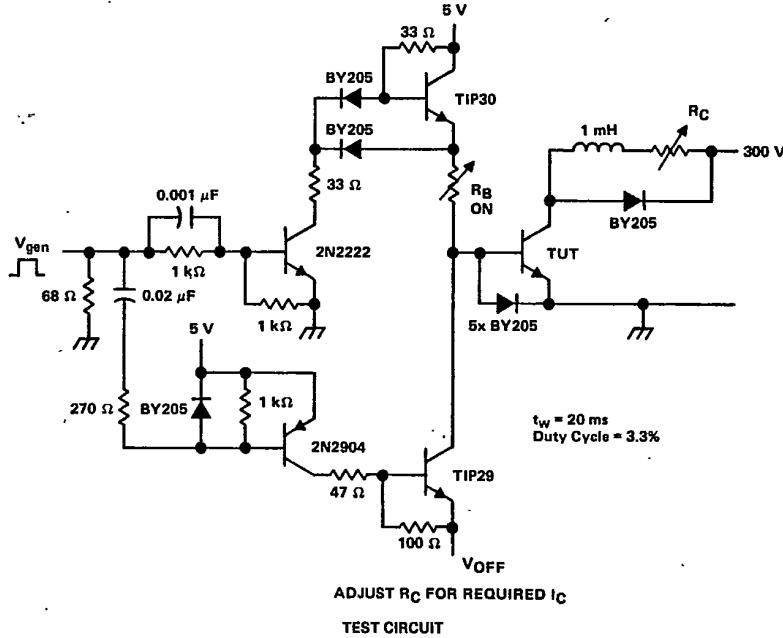
TIPL Devices



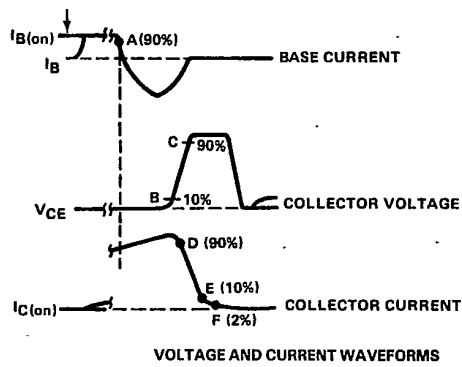
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PARAMETER MEASUREMENT INFORMATION



TIPL Devices



NOTES: A. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r < 15 \text{ ns}$ ,  $R_{in} \geq 10 \Omega$  and  $C_{in} < 11.5 \text{ pF}$ .  
 B. Resistors must be noninductive types.

FIGURE 2. INDUCTIVE-LOAD SWITCHING

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TYPICAL CHARACTERISTICS

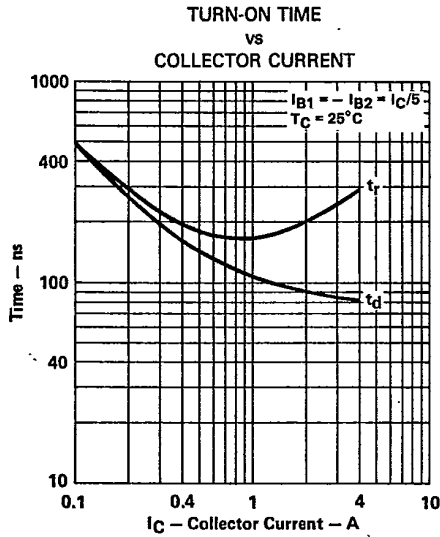


FIGURE 3

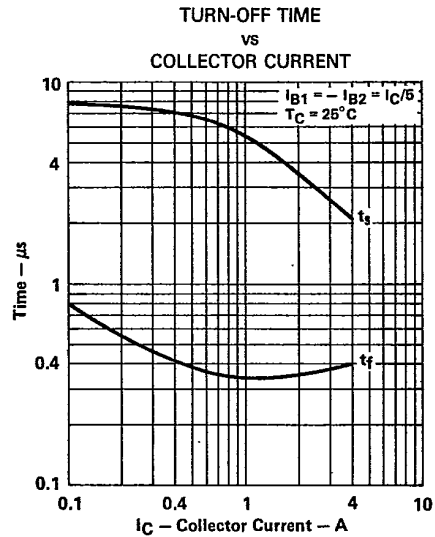


FIGURE 4

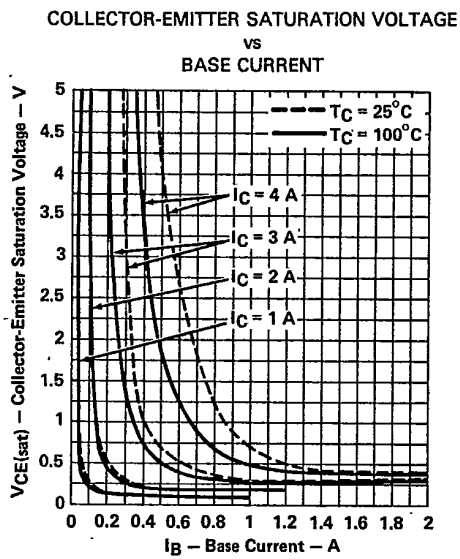


FIGURE 5

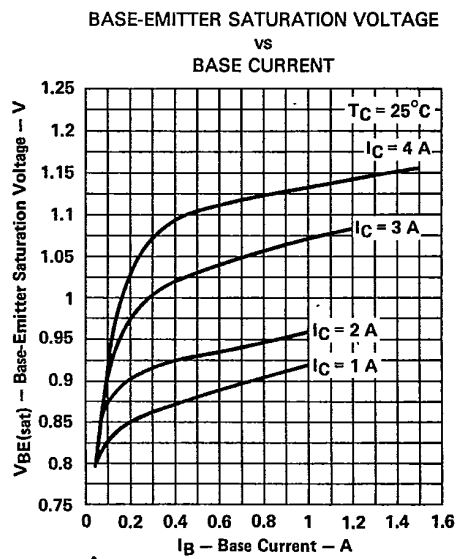


FIGURE 6

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TYPICAL CHARACTERISTICS

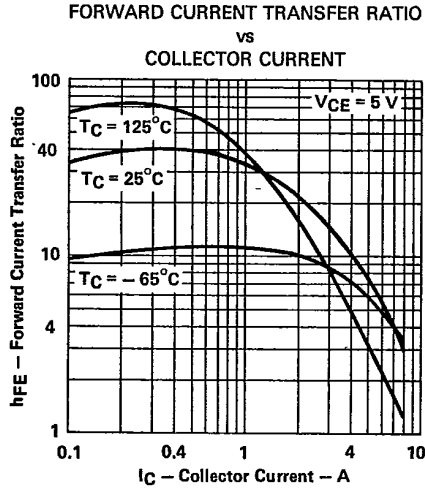


FIGURE 7

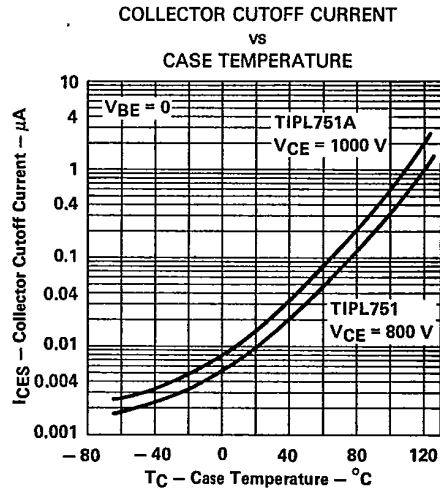


FIGURE 8

MAXIMUM SAFE OPERATING AREA

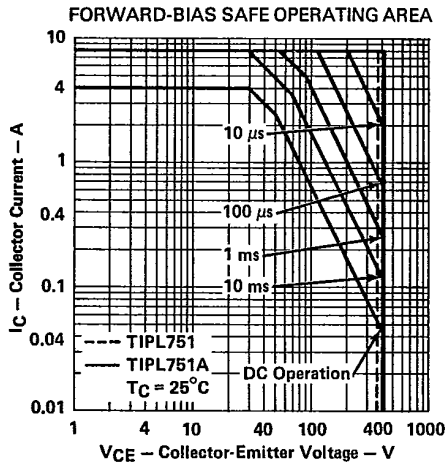


FIGURE 9

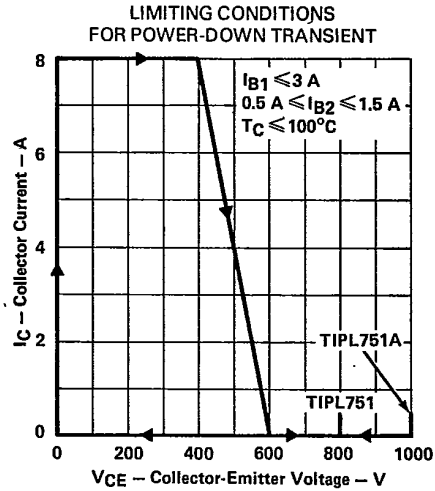


FIGURE 10

TIPL Devices



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THERMAL INFORMATION

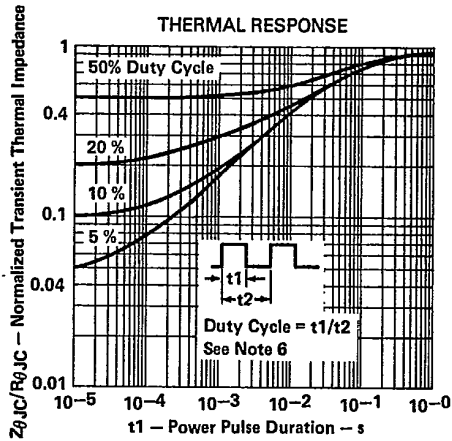


FIGURE 11

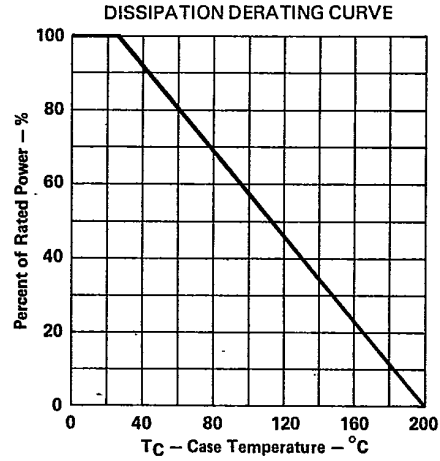


FIGURE 12

NOTE 6: Read time at end of  $t_1$ ,  $T_{J(max)} - T_C = P_{D(peak)} \cdot \left( \frac{Z_{\theta JC}}{R_{\theta JC}} \right) \cdot R_{\theta JC(max)}$ .

TIPL Devices

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